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**To cite this article:** Tomoaki Yazaki, Keisuke Arimoto, Junji Yamanaka & Kosuke O. Hara (28 Jan 2026): Computational material screening for electrode materials of BaSi solar cells, Science and Technology of Advanced Materials: Methods, DOI: [10.1080/27660400.2026.2617671](https://doi.org/10.1080/27660400.2026.2617671)

**To link to this article:** <https://doi.org/10.1080/27660400.2026.2617671>



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Accepted author version posted online: 28 Jan 2026.



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We present a high-throughput screening workflow integrating device simulations and property computations, enabling rapid identification of promising electrode materials for BaSi<sub>2</sub> and broader photovoltaic technologies.

## Computational material screening for electrode materials of BaSi<sub>2</sub> solar cells

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### ARTICLE HISTORY

Compiled January 8, 2026

### ABSTRACT

In this study, we developed a computational material screening workflow for metallic electrodes of BaSi<sub>2</sub> solar cells. Elemental and binary metallic materials in the Materials Project database were screened for four device models with different charge transport layer materials contacting the electrode. The screening criteria included chemical stability, melting point, and work function. In contrast to conventional screening approaches that rely solely on materials descriptors, the present workflow explicitly incorporates device-level performance constraints by using the relationship between the work function and the simulated power conversion efficiency. For melting point evaluation, a linear regression estimation from the cohesive energy and a machine learning model were compared to assess their accuracy, which revealed the higher accuracy of the machine learning model. For work function evaluation, first-principles calculation and another machine learning model were compared, which showed similar accuracies. Considering the computational cost, the machine learning model was used for screening. The threshold of work function screening was determined by device simulations. As a result, promising materials for metallic electrodes were successfully identified. Moreover, the developed screening workflow with high versatility will be applicable to material discovery for other solar cells and semiconductor devices.

### KEYWORDS

Solar cells; Metallic electrode; High-throughput virtual screening; Work function; Melting point; Density functional theory

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# 1. Introduction

The selection of appropriate electrode materials is crucial for improving the performance of electronic and energy conversion devices, such as solar cells, thermoelectric devices, and MOSFETs [1–7]. In particular, the metallic electrode of a solar cell significantly affects carrier transport efficiency, thereby influencing the overall power conversion efficiency (PCE). Additionally, it is essential to have a high melting point ( $T_m$ ) to withstand high temperature growth and annealing of upper layers and to prevent unintended chemical reactions at the interface. It is challenging to identify optimal electrode materials by comprehensively considering band alignment,  $T_m$ , and chemical reactivity.

The conventional selection of metallic materials has been based on empirical rules and trial-and-error methods, making it challenging to comprehensively evaluate multidimensional material properties. Additionally, the material search space was limited, restricting the number of materials considered. Computational material screening is a powerful approach that screens a huge set of data in databases based on computed properties [8]. This approach can accelerate the discovery of ideal materials in a rational way.

The focus of this study is the metallic electrode of  $\text{BaSi}_2$  solar cells.  $\text{BaSi}_2$  has a band gap ( $E_g$ ) of 1.3 eV, high optical absorption coefficients ( $\geq 10^4 \text{ cm}^{-1}$  for photon energies over  $E_g$ ) [9–11], and long minority carrier lifetime (up to 27  $\mu\text{s}$ ) [12–14], making it a promising light-absorbing material for solar cells. However, the maximum PCE of  $\text{BaSi}_2$  solar cells reported to date remains around 10% [15], which is partly attributed to the lack of an optimized device structure. In particular,  $\text{BaSi}_2$  has a relatively low electron affinity of 3.2 eV [16] compared to other solar cell absorbers, making it difficult to use the device architectures of other solar cells.

In previous studies, we adopted a double heterojunction structure and searched for materials for the electron transport layer (ETL) and hole transport layer (HTL) by computational material screening, successfully identifying optimal materials [17]. The most promising materials among them include  $\text{Sm}_2\text{O}_3$ , 6H-SiC, and 4H-SiC for ETL and BaS for HTL because of the best band alignment, compositional simplicity, and synthesizability. Our screening workflow is unique in that it relies not only on material descriptors but also on device-level performance constraints. This allows us to estimate the expected PCE with the selected materials. The estimated PCE with the identified materials exceeded 30%. The thin film deposition processes for these layers are currently being developed [18, 19]. However, suitable materials for the transparent conductive electrode and back metal electrode have not been explored. In particular, the selection of an appropriate back electrode material poses a challenge due to the large number of candidate materials compared to transparent conductive materials.

In this study, we develop a device-simulation-coupled computational material screening procedure for metallic electrodes to identify the optimal electrode materials for double heterojunction  $\text{BaSi}_2$  solar cells. Particular focus is on  $T_m$  and work function ( $\phi_m$ ).  $T_m$  screening is desirable for  $\text{BaSi}_2$  solar cells because the optical properties of  $\text{BaSi}_2$  are improved by annealing at 850–1000 °C [20], requiring materials with high  $T_m$ . Two methods are investigated for rapidly and accurately estimating  $T_m$  and  $\phi_m$ . Based on the result, an effective procedure of computational material screening is proposed for electrode materials of solar cells. Because the ETL and HTL materials contacting the electrode affect the screening results, we studied four different device structures with  $\text{Sm}_2\text{O}_3$ , 6H-SiC, and 4H-SiC as ETL materials and BaS as the HTL material in this study. Promising candidate materials are identified for different device structures.

## 2. Methods

### 2.1. Device simulations

Device simulations were conducted using the console version of wxAMPS [21, 22] under AM 1.5 illumination with an intensity of  $1000 \text{ W/m}^2$  to investigate the required conditions for the  $\phi_m$  of the electrode materials. Four device models shown in Fig. 1 were investigated. All four models consist of transparent conductive film (TCF, 100 nm), HTL (100 nm),  $\text{BaSi}_2$  ( $2 \mu\text{m}$  [17]), ETL (100 nm), and metallic electrode. Three of the models have ETL at the back side, contacting with metallic electrodes, while the other one has HTL at the back side. The ETL materials selected were  $\text{Sm}_2\text{O}_3$ , 4H-SiC, and 6H-SiC, while BaS was chosen for HTL.

The material properties were basically referenced from literatures, as summarized in Table 1. Absorption coefficients of  $\text{BaSi}_2$  were taken from Ref. [23] with neglecting the values for photon energies below  $E_g$ . However, the absorption coefficients for ETL, HTL, and TCF were assumed for simplicity to be step functions, which were  $10^5 \text{ cm}^{-1}$  for photon energies over  $E_g$ , and zero otherwise. Electron densities in  $\text{BaSi}_2$  and ETL were assumed to be  $1 \times 10^{16} \text{ cm}^{-3}$  [24–26] and  $1 \times 10^{14} \text{ cm}^{-3}$ , respectively, while hole density in HTL was assumed to be  $1 \times 10^{14} \text{ cm}^{-3}$ . The conductivity type of TCF was assumed to be either n- or p-type when contacting with ETL or HTL, respectively, with carrier density of  $1 \times 10^{21} \text{ cm}^{-3}$ .

For  $\text{BaSi}_2$ , the effective density of states in the conduction band ( $N_c$ ), the effective density of states in the valence band ( $N_v$ ), and the radiative recombination coefficient ( $B$ ) are  $N_c = 6.76 \times 10^{18} \text{ cm}^{-3}$ ,  $N_v = 1.07 \times 10^{19} \text{ cm}^{-3}$ , and  $B = 1.09 \times 10^{-11} \text{ cm}^3 \text{ s}^{-1}$  [17]. These values were also used for ETL, HTL, and TCF.

All carrier mobilities were assumed to be  $100 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$ . The dielectric constant of TCF was assumed to be the same as  $\text{BaSi}_2$ . The  $E_g$  and electron affinity of TCF were set to the optimal values that maximize PCE for given models. The front- and back-side reflectances were set to 0 and 1, respectively. The effective surface recombination velocities for both the front and back sides were assumed to be  $10^7 \text{ cm/s}$ . Bulk defects and band tailing were not considered, and the intraband tunneling mode was employed as the simulation mode.

Metal electrodes were not explicitly included in the models. Instead, effects of different  $\phi_m$  were considered by different potential barrier heights (PBH) at the back surfaces. For the ETL/metal electrode interface, PBH corresponds to the difference between the  $\phi_m$  of the electrode and the electron affinity of ETL, while for the HTL/electrode interface, PBH corresponds to the difference between the  $\phi_m$  of the electrode and the ionization potential of HTL.

### 2.2. Computational material screening

The Materials Project database [27] was screened using the mp-api and pymatgen [28] Python library (access in June 2023). The search space was limited to single and binary compounds free from rare (less abundant than Ag in the Earth’s crust), highly toxic (Be, Cd, As, Hg, Pb, Tl), and radioactive elements. Only metallic materials were included by setting  $E_g = 0 \text{ eV}$ . Additionally, to ensure the stability of the materials, we applied the condition that the energy above the convex hull = 0 eV.

First, we evaluated interfacial chemical reactivity. The interfacial chemical reactivity was evaluated using the InterfacialReactivity class [30] of pymatgen. We excluded the materials

that can thermodynamically react with the adjacent layer.

$T_m$  was evaluated by two methods to find out a rapid and accurate method that is suitable for high-throughput screening. One is based on the relationship between the  $T_m$  and cohesive energies ( $E_{\text{coh}}$ ). The  $E_{\text{coh}}$  of compounds was calculated by Miedema's theory using Miedema.py [31, 32]. Linear regression was analyzed between the  $E_{\text{coh}}$  and the "temperature for congruent melting" data from the Materials Platform for Data Science (MPDS) for randomly selected 93 binary compounds. The intercept was set to zero. This regression line allowed us to estimate the  $T_m$ . The other method uses a machine learning model developed by Hong *et al.* [33]. This machine learning model was trained on approximately 10,000 compound data [33], and predicts a  $T_m$  using a graph neural network and a residual neural network. The accuracies of these methods were evaluated by the prediction errors for different randomly selected data from MPDS.

Appropriate estimation methods for  $\phi_m$  were also investigated. We compared the density functional theory (DFT) and machine learning methods using the experimental work function data [34] for elemental metals as reference. We used Quantum Espresso [35, 36] for DFT calculations.  $\phi_m$  was estimated as the difference between the Fermi and vacuum levels using slab models of thicker than 20 Å with 20 Å vacuum regions. Slab models were generated using the pymatgen library [37, 28]. If slabs with several different surface terminations were prepared, their  $\phi_m$  were averaged. All calculations were performed with the Perdew–Burke–Ernzerhof functional tuned for solids (PBEsol) [38] in the generalized gradient approximation (GGA).  $\phi_m$  were estimated after structural relaxation. Gaussian smearing with the spreading of 68 meV was used for occupations. We followed our previous papers [26, 17] for other parameter settings. The machine learning model for  $\phi_m$  investigated was the random forest model developed by Schindler *et al.* [39]. This model was trained on a dataset comprising 58,332  $\phi_m$  and 33,631 exfoliation energies obtained from high-throughput DFT calculations. In this study, we averaged  $\phi_m$  over different surface terminations to obtain a representative  $\phi_m$  for a given crystal plane. This approach was adopted because identifying the most probable termination for each material is impractical, even though actual surface terminations depend on crystal growth conditions.  $\phi_m$  of 33 elemental metals were evaluated by both methods, and the accuracy was evaluated using the experimentally reported  $\phi_m$  [34] as reference values.

### 3. Results and discussion

#### 3.1. Device simulations

Figures 2(a) and 2(b) show the band alignments of the model (C) in Fig. 1 under dark conditions with PBH = 0.0 and 0.5 eV, respectively. In the figures, the metallic electrode is assumed to be present on the right side of the  $\text{Sm}_2\text{O}_3$  ETL. Obviously, this band alignment with PBH = 0.0 eV allows efficient charge separation with small potential barriers for electrons toward the back electrode through  $\text{Sm}_2\text{O}_3$  ETL (0.26 eV) and for holes toward the front TCF through BaS HTL (0.15 eV). On the other hand, with PBH = 0.5 eV, the band energy levels of ETL and  $\text{BaSi}_2$  near ETL rise toward the back electrode. This band bending obstructs electron transport and reduces PCE. To identify the  $\phi_m$  range where smooth charge transport is assured, PCE was simulated with different PBH values.

Figures 3(a)–(d) show the PCE as functions of  $\phi_m$  of metallic electrodes for the models (A)–(D) in Fig. 1, respectively. The horizontal dashed line in each panel of Fig. 3 indicates a

PCE of 30%. With the models (A)–(C), PCE decreases with increasing  $\phi_m$ . This is because the band energy levels of the ETL and BaSi<sub>2</sub> near ETL increase, as shown in the insets. The thresholds of the  $\phi_m$  where PCE starts to decrease are 3.90, 3.61, and 3.32 eV for the models (A)–(C), respectively. These thresholds corresponding to PBH of 0.3 eV, which is presumably the highest barrier that electrons can overcome. On the other hand, with the model (D), PCE decreases with decreasing  $\phi_m$ , because the band energy levels are lowered and the barriers for holes are generated. The threshold where PCE starts to decrease is 4.42 eV, which again corresponds to the PBH of 0.3 eV for holes. This 0.3 eV PBH threshold is a useful criterion that could be applicable to various types of solar cells. For the purpose of electrode materials selection of this study, the  $\phi_m$  thresholds serve as criteria for computational material screening.

### 3.2. Computational material screening

The workflow of computational material screening for metallic electrode materials is shown in Fig. 4. The search space was defined by  $E_g = 0$  eV, the energy above the convex hull = 0 eV, and elemental and binary substances without rare, toxic, and radioactive elements described in Methods. At this stage, 1,830 metallic materials were included in the candidate list. The interface reactivity screening decreased the number of candidates to 567, 567, 878, and 1483 for models (A)–(D), respectively. To further screen the materials by  $T_m$ , we compared two estimation methods to select an appropriate method: linear regression using Miedema's  $E_{\text{coh}}$  and the machine learning model.

The physical principle of melting indicates that a high  $E_{\text{coh}}$  leads to a high  $T_m$ , which is the basis of estimating  $T_m$  from  $E_{\text{coh}}$ . Actually,  $T_m$  is reported to be roughly proportional to  $E_{\text{coh}}$  in Laves phases [31]. We determined the regression line between  $E_{\text{coh}}$  and  $T_m$  using the data for random binary metallic compounds in MPDS.  $E_{\text{coh}}$  was calculated using Miedema's theory [40, 31]. Figure 5 shows the  $T_m$  plotted against  $E_{\text{coh}}$  together with the regression line. A positive correlation is confirmed between  $T_m$  and  $E_{\text{coh}}$ . The coefficient of determination was 0.85 according to Kvålseth's  $R_2^8$  definition [41]. The obtained regression equation is  $(T_m / \text{K}) = 5.27 \times (E_{\text{coh}} / \text{kJmol}^{-1})$ .

Figure 6 compares the  $T_m$  estimated using the regression line derived from  $E_{\text{coh}}$  and those predicted by the machine learning model developed by Hong *et al* [33], with the reference values obtained from MPDS. Different material data were used from those used for the linear regression. The accuracy of the  $T_m$  estimation was evaluated using the mean absolute error (MAE). The MAE of the linear regression was 616.7 K, while that of the machine learning model was 69.6 K, showing the higher accuracy of the machine learning model than the linear regression method. The estimation based on  $E_{\text{coh}}$  is reported effective for materials with specific structures, such as Laves phases [31]. The current evaluation indicates that the simple linear regression is not as effective as machine learning for materials with various crystal structures. Therefore, we employed the machine learning model [33] for  $T_m$  estimation.

We screened the candidate materials with the  $T_m$  criterion of 1000 °C because annealing at 1000 °C is reported to enhance the photoresponsivity of BaSi<sub>2</sub> [20], and hence, the metallic electrode is possibly exposed to high temperatures up to 1000 °C during solar cell fabrication. After the  $T_m$  screening step, 388, 388, 624, and 1136 candidates were retained for models (A)–(D) in Fig. 1, respectively.

The last screening step involved  $\phi_m$ , which is the essential parameter influencing the PCE, as shown in Fig. 3. DFT is the most reliable method to computationally estimate the  $\phi_m$  of materials, while Schindler *et al.* recently reported a machine learning model using random forest for  $\phi_m$  prediction [39]. We investigated the prediction accuracy of these two methods by estimating the  $\phi_m$  of 33 elemental metals using the reported experimental values [34] as reference.

Figure 7 shows the  $\phi_m$  of elemental metals estimated by DFT and the machine learning model. The (100) surface was selected for all metals. The average  $\phi_m$  of different surface terminations is shown. The MAEs between the estimated and reference values was 0.30 eV for DFT and 0.31 eV for the machine learning model. This result indicates that both methods estimate the  $\phi_m$  with similar accuracy. This is possibly because the machine learning model was trained on the DFT calculation data, leading to a prediction error comparable to that of DFT. The data used to train the machine learning model were prepared with ionically unrelaxed slabs, while our DFT calculations involved ionic relaxations of slab models. Regardless of this difference, the machine learning model worked well. Additionally, computational costs are greatly lower with the machine learning model than DFT. Therefore, screening was conducted using the machine learning model [39].

To represent the work function of a polycrystalline surface, work functions calculated by the machine learning model for inequivalent surface planes were averaged. Miller indices up to 1 were considered. In principle, a weighted average that accounts for the exponential dependence of thermionic emission on the work function should be used, with the fractional areas as weights [42]. However, these fractional areas cannot be reliably estimated. Therefore, we adopted a simple arithmetic average over inequivalent crystal planes. To assess the validity of this approach, we evaluated the work functions of 43 polycrystalline elements, for which experimental polycrystalline values are available [34]. The resulting MAE was 0.26 eV, comparable to that obtained for the (100) surface. This result indicates that averaging over inequivalent planes provides sufficient accuracy for screening purposes.

The  $\phi_m$  screening was performed with the criterion that the PCE should exceed 30%, which was derived from the simulation results shown in Fig. 3. This step resulted in 197, 89, 41, and 233 candidates for the models (A)–(D) in Fig.1, respectively. These final candidates and their properties are summarized in Table 2–5.

When the ETL was placed on the back side [models (A)–(C)], the number of candidate materials was smaller than otherwise [model (D)]. This is due to the imposed conditions of high  $T_m$  and low  $\phi_m$ . It is generally known that transition metals with high  $T_m$  tend to have high  $\phi_m$  [43–45]. In contrast, rare-earth elements tend to exhibit both high  $T_m$  and low  $\phi_m$  [46, 34, 47], whereas alkaline earth metals, despite having low  $T_m$ , also tend to have low  $\phi_m$  [48, 34]. As a result, many of the final candidates for models (A)–(C) contain one of rare earth and alkaline earth elements. Among these models, in particular model (A), the ETL in contact with the electrode has a relatively large electron affinity, so the allowable upper limit (threshold) of the electrode work function is higher than in the other models. As a result, more materials satisfy this threshold, and the number of candidates that passes the screening criteria is correspondingly larger. Then, to further screen materials, the candidates were arranged in the order of electrical conductivity (accurately, electrical conductivity divided by the relaxation time), as shown in Fig. 8. The electrical conductivity was referenced from Ref. [49], where a large dataset of transport data were obtained by DFT and BoltzTraP calculations assuming a constant relaxation time. Materials without available data were not included in the figure. This figure shows that ScGa<sub>3</sub>, CaAl<sub>2</sub>, GdS, and PrSi<sub>2</sub> are especially promising among the final candidates for model (A).

Although they are promising from the viewpoints of physical and chemical properties, expensive and air-sensitive characters of these materials possibly make their usage practically difficult.

On the other hand, in model Fig. 1 (D), a relatively large number of candidate materials were obtained. This is because the screening conditions required high  $T_m$  and high  $\phi_m$ , leading to the selection of many transition metal compounds. The large number of candidate materials including transition metal compounds suggests that model (D) is promising for practical implementation. Figure 9 shows the electrical conductivity of the candidates. The high rank materials include elemental metals: Cu, W, Fe, and Ni. They are accessible stable materials and therefore promising for practical implementation. Thus, the computational screening workflow proposed in this study is useful for finding out promising electrode materials as well as for selecting versatile device models.

As a final supplementary investigation, we also applied the proposed screening workflow to conventional crystalline Si solar cells. The screened candidates ranked practical materials, such as Al and Ag, among the top candidates, demonstrating the effectiveness of the workflow. Detailed procedures and results are provided in the Supplemental Material.

## 4. Conclusions

We developed a computational material screening workflow for electrode materials of  $\text{BaSi}_2$  solar cells. In particular, the accuracy of  $T_m$  and  $\phi_m$  estimations was evaluated by comparing conventional methods with machine learning predictions, demonstrating that efficient screening can be performed for a wide variety of materials with machine learning models. Device simulations revealed the thresholds of  $\phi_m$  for four different device models, which were used as one of the screening criteria. Based on the large number of final candidate materials that satisfied the screening conditions, two device configurations were identified as particularly promising for practical implementations: model (A) with 6H-SiC ETL and model (D) with BaSi HTL on a metallic electrode. Among the screened candidates,  $\text{ScGa}_3$ ,  $\text{CaAl}_2$ , GdS, and  $\text{PrSi}_2$  were identified as promising electrode materials for model (A) due to their high electrical conductivity, while Cu, W, Fe, and Ni were selected for model (D). Notably, some of these electrode materials have not yet been reported for  $\text{BaSi}_2$  solar cells. The screening workflow developed in this study is highly versatile and is applicable not only to  $\text{BaSi}_2$  solar cells but also to other solar cells and semiconductor devices.

## Acknowledgment

This work was partly supported by the Murata Science Foundation.

## Disclosure statement

The authors report there are no competing interests to declare..

## Data availability

The data will be available on request from the corresponding authors.

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**Figure 1.** Device models used for simulations.

**Figure 2.** The calculated band alignments of the model (C) in Fig. 1 with PBH = (a) 0.0 and (b) 0.5 eV under dark conditions. Upper blue line denotes the conduction band minimum while the lower orange line denotes the valence band maximum.

**Figure 3.** (a)–(d) Simulated PCE of solar cells as functions of the  $\phi_m$  of metallic electrodes in models (A)–(D), where the electrodes are in contact with 6H-SiC, 4H-SiC,  $\text{Sm}_2\text{O}_3$ , and BaS, respectively. The red dashed line indicates a PCE of 30%. The insets show the band alignments near the back electrode for specific work functions. CB and VB denote the conduction and valence bands, respectively.

**Figure 4.** Workflow of computational material screening for metallic electrodes of solar cells proposed in this study.

**Figure 5.**  $T_m$  plotted against  $E_{\text{coh}}$  of randomly selected binary metallic compounds, along with the regression line.

**Figure 6.** Comparison of the  $T_m$  of binary metallic compounds estimated by the linear regression (circles) and the machine learning model [33] (squares) with the reference values.

**Figure 7.** Comparison of the  $\phi_m$  of elemental metals estimated by DFT and the machine learning model [39]. The surface orientation selected was (100) for all data.

**Figure 8.** Electrical conductivity of the candidate materials for model (A). The electrical conductivity divided by the relaxation time is shown.

**Figure 9.** Electrical conductivity of the candidate materials for model (D). The electrical conductivity divided by the relaxation time is shown.

**Table 1.** Material properties used for device simulations.

	Material				
Parameter	BaSi <sub>2</sub>	BaS	Sm <sub>2</sub> O <sub>3</sub>	6H-SiC	4H-SiC
Dielectric constant	14 [50]	15 [27]	15 [51]	8 [52]	8 [52]
$E_g$ (eV)	1.3 [9, 10, 11]	3.81 [53]	5.16 [54, 55]	3.0 [56]	3.2 [56]
Electron affinity (eV)	3.2 [16]	0.84 [57]	2.94 [54, 55]	3.5 [56]	3.2 [56]

Formula	$T_m$ (K)	$\phi_m$ (eV)	Formula	$T_m$ (K)	$\phi_m$ (eV)	Formula	$T_m$ (K)	$\phi_m$ (eV)
Ba <sub>3</sub> Ge <sub>4</sub>	1423	3.67	EuSi	1597	3.73	PrS	2478	2.60
Ba <sub>3</sub> Ge <sub>5</sub>	1418	3.48	EuSi <sub>2</sub>	1756	3.73	PrSb	2384	3.30
Ba <sub>3</sub> Si <sub>4</sub>	1412	3.90	EuSn	1373	3.53	PrSi	1934	3.69
Ba <sub>5</sub> Sb <sub>3</sub>	1405	2.90	GdAl <sub>2</sub>	1774	3.69	PrSi <sub>2</sub>	1942	3.56
BaAl <sub>4</sub>	1325	3.50	GdAl <sub>3</sub>	1761	3.70	PrSn <sub>2</sub>	1437	3.55
BaGa <sub>2</sub>	1290	3.08	GdGa <sub>2</sub>	1635	3.54	PrSn <sub>3</sub>	1434	3.33
BaGa <sub>4</sub>	1277	3.56	GdGa <sub>3</sub>	1642	3.78	ScAl <sub>3</sub>	1654	3.82
BaGe	1426	3.41	GdGe	2041	3.52	ScGa <sub>3</sub>	1393	3.73
BaSi	1413	3.38	GdN	2994	3.23	ScGe	2276	3.82
BaSn	1416	3.29	GdP	2996	3.52	ScN	2747	3.44
Ca <sub>11</sub> Sb <sub>10</sub>	1310	3.50	GdS	2530	2.87	ScP	2569	3.75
CaAl <sub>2</sub>	1342	3.70	GdSb	2421	3.51	ScSb	2488	3.70
CaGa <sub>2</sub>	1277	3.79	GdSi	2091	3.81	ScSi	2259	3.86
CaGe	1432	3.83	GdSn <sub>2</sub>	1396	3.62	Sm <sub>11</sub> Sn <sub>10</sub>	1758	3.43
CaGe <sub>2</sub>	1308	3.85	Ho <sub>3</sub> Ge <sub>4</sub>	2089	3.75	Sm <sub>3</sub> Ge <sub>5</sub>	1743	3.75
CaSi	1524	3.67	Ho <sub>3</sub> Ge <sub>5</sub>	1788	3.84	SmAl <sub>3</sub>	1737	3.70
CaSn	1374	3.25	Ho <sub>3</sub> Sn <sub>7</sub>	1362	3.82	SmGa <sub>2</sub>	1640	3.47
Ce <sub>3</sub> Al <sub>11</sub>	1530	3.76	HoAl <sub>3</sub>	1763	3.82	SmGa <sub>3</sub>	1646	3.76
Ce <sub>3</sub> Ge <sub>5</sub>	1755	3.78	HoGa <sub>2</sub>	1583	3.57	SmGe	1790	3.56
Ce <sub>3</sub> Sn <sub>7</sub>	1434	3.74	HoGa <sub>3</sub>	1596	3.84	SmS	2288	3.80
Ce <sub>4</sub> Ge <sub>7</sub>	1752	3.67	HoGe	2161	3.73	SmSi	2064	3.44
Ce <sub>4</sub> H <sub>11</sub>	1333	3.66	HoP	2713	3.60	SmSn <sub>2</sub>	1373	3.58
Ce <sub>7</sub> O <sub>12</sub>	2587	3.77	HoS	2550	3.07	SmSn <sub>3</sub>	1381	3.40
CeAl <sub>3</sub>	1591	3.85	HoSb	2398	3.59	Sr <sub>5</sub> Sb <sub>3</sub>	1309	3.27
CeGa <sub>3</sub>	1707	3.73	HoSi	2132	3.71	SrAl <sub>4</sub>	1327	3.51
CeGa <sub>6</sub>	1591	3.87	HoSn <sub>2</sub>	1357	3.85	SrGa <sub>2</sub>	1283	3.27
CeN	3025	2.97	La <sub>2</sub> H <sub>5</sub>	1320	3.42	SrGa <sub>4</sub>	1276	3.63
CeP	2986	3.31	La <sub>2</sub> H <sub>5</sub>	1320	3.58	SrGe	1426	3.58
CeS	2652	2.65	La <sub>2</sub> Sn <sub>3</sub>	1445	3.46	SrGe <sub>2</sub>	1405	3.71
CeSb	2073	3.29	La <sub>3</sub> Al <sub>11</sub>	1524	3.82	SrSi	1421	3.85
CeSb <sub>2</sub>	1829	3.89	La <sub>3</sub> Ge <sub>5</sub>	1748	3.66	SrSn	1394	3.49
CeSn <sub>3</sub>	1433	3.33	La <sub>3</sub> Sn <sub>7</sub>	1436	3.58	Tb <sub>3</sub> Ge <sub>4</sub>	2059	3.61
Dy <sub>3</sub> Ge <sub>4</sub>	2095	3.69	LaGa <sub>2</sub>	1725	3.34	Tb <sub>3</sub> Ge <sub>5</sub>	1888	3.76
Dy <sub>3</sub> Ge <sub>5</sub>	1868	3.75	LaGe	1758	3.25	Tb <sub>3</sub> Sn <sub>7</sub>	1374	3.78
Dy <sub>5</sub> S <sub>7</sub>	1944	3.86	LaP	2727	3.27	Tb <sub>5</sub> S <sub>7</sub>	1963	3.81
Dy <sub>5</sub> Sn <sub>11</sub>	1358	3.80	LaS	2429	2.47	TbAl <sub>3</sub>	1762	3.71

DyAl <sub>3</sub>	1760	3.72	LaSb	2051	3.29	TbGa <sub>2</sub>	1573	3.55
DyGa <sub>2</sub>	1589	3.57	LaSb <sub>2</sub>	1801	3.86	TbGa <sub>3</sub>	1551	3.72
DyGa <sub>3</sub>	1608	3.74	LaSn <sub>3</sub>	1433	3.27	TbGe	2137	3.68
DyGe	2138	3.36	Lu <sub>11</sub> Ge <sub>10</sub>	2253	3.65	TbS	2602	3.90
DyP	2690	3.60	Lu <sub>3</sub> Ge <sub>4</sub>	2107	3.88	TbSi	2107	3.41
DyS	2557	3.01	LuAl <sub>3</sub>	1741	3.73	TbSn <sub>2</sub>	1372	3.69
DySb	2383	3.58	LuGa <sub>2</sub>	1572	3.80	TiF <sub>3</sub>	1707	3.55
DySi	2119	3.86	LuGa <sub>3</sub>	1530	3.67	TiN	3225	3.55
Er <sub>3</sub> Ge <sub>4</sub>	2162	3.75	LuGe <sub>2</sub>	1574	3.85	Tm <sub>3</sub> Ge <sub>4</sub>	2125	3.82
Er <sub>3</sub> Sn <sub>7</sub>	1351	3.83	LuP	2534	3.62	TmAl <sub>3</sub>	1758	3.79
ErAl <sub>3</sub>	1758	3.65	LuSb	2394	3.61	TmGa <sub>2</sub>	1573	3.76
ErGa <sub>2</sub>	1578	3.61	LuSn <sub>2</sub>	1335	3.87	TmGa <sub>3</sub>	1565	3.81
ErGa <sub>3</sub>	1584	3.79	Nd <sub>2</sub> Sn <sub>3</sub>	1437	3.52	TmGe	2211	3.75
ErGe	2211	3.84	Nd <sub>3</sub> Ge <sub>5</sub>	1802	3.74	TmP	2636	3.64
ErP	2595	3.62	Nd <sub>3</sub> Sn <sub>7</sub>	1430	3.63	TmSi	2139	3.83
ErS	2394	3.10	NdAl <sub>3</sub>	1721	3.63	TmSn <sub>2</sub>	1334	3.74
ErSb	2348	3.60	NdGa <sub>2</sub>	1732	3.39	Y <sub>3</sub> Ge <sub>4</sub>	2146	3.60
ErSi	2141	3.85	NdGa <sub>3</sub>	1716	3.75	Y <sub>3</sub> Ge <sub>5</sub>	1928	3.77
ErSn <sub>2</sub>	1346	3.83	NdGe	1797	3.50	YAl <sub>3</sub>	1754	3.66
Eu <sub>16</sub> Sb <sub>11</sub>	1811	3.49	NdP	2842	3.36	YGa <sub>2</sub>	1630	3.56
Eu <sub>3</sub> Ge <sub>5</sub>	1330	3.61	NdS	2525	2.64	YGa <sub>3</sub>	1631	3.80
Eu <sub>3</sub> P <sub>4</sub>	1609	3.89	NdSb	2384	3.29	YGe	2193	3.71
Eu <sub>5</sub> Sb <sub>3</sub>	1791	3.24	NdSi	1941	3.59	YP	2697	3.59
EuAl <sub>4</sub>	1366	3.64	NdSn <sub>2</sub>	1433	3.54	YSi	2124	3.79
EuGa <sub>2</sub>	1292	3.51	NdSn <sub>3</sub>	1428	3.35	YSn <sub>2</sub>	1356	3.85
EuGa <sub>4</sub>	1286	3.77	Pr <sub>2</sub> Sn <sub>3</sub>	1440	3.50	Zr <sub>5</sub> Zn <sub>39</sub>	1303	3.81
EuGe	1423	3.56	PrAl <sub>3</sub>	1659	3.85	ZrAl <sub>3</sub>	1860	3.81
EuO	2246	3.03	PrGa <sub>2</sub>	1736	3.37	ZrC	3534	3.85
EuP	2256	3.38	PrGa <sub>3</sub>	1725	3.73	ZrGa <sub>3</sub>	1650	3.90
EuS	2534	2.85	PrGe	1768	3.50			

Table 2.: List of candidate metallic materials for model (A): 6H-SiC contacting layer. The estimated  $T_m$  and  $\phi_m$  are also summarized.

Formula	$T_m$ (K)	$\phi_m$ (eV)	Formula	$T_m$ (K)	$\phi_m$ (eV)	Formula	$T_m$ (K)	$\phi_m$ (eV)
Ba <sub>3</sub> Ge <sub>5</sub>	1418	3.48	EuS	2534	2.85	NdSn <sub>2</sub>	1433	3.54
Ba <sub>5</sub> Sb <sub>3</sub>	1405	2.90	EuSn	1373	3.53	NdSn <sub>3</sub>	1428	3.35

BaAl <sub>4</sub>	1325	3.50	GdGa <sub>2</sub>	1635	3.54	Pr <sub>2</sub> Sn <sub>3</sub>	1440	3.50
BaGa <sub>2</sub>	1290	3.08	GdGe	2041	3.52	PrGa <sub>2</sub>	1736	3.37
BaGa <sub>4</sub>	1277	3.56	GdN	2994	3.23	PrGe	1768	3.50
BaGe	1426	3.41	GdP	2996	3.52	PrS	2478	2.60
BaSi	1413	3.38	GdS	2530	2.87	PrSb	2384	3.30
BaSn	1416	3.29	GdSb	2421	3.51	PrSi <sub>2</sub>	1942	3.56
Ca <sub>11</sub> Sb <sub>10</sub>	1310	3.5	HoGa <sub>2</sub>	1583	3.57	PrSn <sub>2</sub>	1437	3.55
CaSn	1374	3.25	HoP	2713	3.60	PrSn <sub>3</sub>	1434	3.33
CeN	3025	2.97	HoS	2550	3.07	ScN	2747	3.44
CeP	2986	3.31	HoSb	2398	3.59	Sm <sub>11</sub> Sn <sub>10</sub>	1758	3.43
CeS	2652	2.65	La <sub>2</sub> H <sub>5</sub>	1320	3.42	SmGa <sub>2</sub>	1640	3.47
CeSb	2073	3.29	La <sub>2</sub> H <sub>5</sub>	1320	3.58	SmGe	1790	3.56
CeSn <sub>3</sub>	1433	3.33	La <sub>2</sub> Sn <sub>3</sub>	1445	3.46	SmSi	2064	3.44
DyGa <sub>2</sub>	1589	3.57	La <sub>3</sub> Sn <sub>7</sub>	1436	3.58	SmSn <sub>2</sub>	1373	3.58
DyGe	2138	3.36	LaGa <sub>2</sub>	1725	3.34	SmSn <sub>3</sub>	1381	3.40
DyP	2690	3.60	LaGe	1758	3.25	Sr <sub>5</sub> Sb <sub>3</sub>	1309	3.27
DyS	2557	3.01	LaP	2727	3.27	SrAl <sub>4</sub>	1327	3.51
DySb	2383	3.58	LaS	2429	2.47	SrGa <sub>2</sub>	1283	3.27
ErGa <sub>2</sub>	1578	3.61	LaSb	2051	3.29	SrGe	1426	3.58
ErS	2394	3.10	LaSn <sub>3</sub>	1433	3.27	SrSn	1394	3.49
ErSb	2348	3.60	LuSb	2394	3.61	TbGa <sub>2</sub>	1573	3.55
Eu <sub>16</sub> Sb <sub>11</sub>	1811	3.49	Nd <sub>2</sub> Sn <sub>3</sub>	1437	3.52	TbSi	2107	3.41
Eu <sub>3</sub> Ge <sub>5</sub>	1330	3.61	NdGa <sub>2</sub>	1732	3.39	TiF <sub>3</sub>	1707	3.55
Eu <sub>5</sub> Sb <sub>3</sub>	1791	3.24	NdGe	1797	3.50	TiN	3225	3.55
EuGa <sub>2</sub>	1292	3.51	NdP	2842	3.36	Y <sub>3</sub> Ge <sub>4</sub>	2146	3.60
EuGe	1423	3.56	NdS	2525	2.64	YGa <sub>2</sub>	1630	3.56
EuO	2246	3.03	NdSb	2384	3.29	YP	2697	3.59
EuP	2256	3.38	NdSi	1941	3.59			

Table 3.: List of candidate metallic materials for model (B): 4H-SiC contacting layer. The estimated  $T_m$  and  $\phi_m$  are also summarized.

Formula	$T_m$ (K)	$\phi_m$ (eV)	Formula	$T_m$ (K)	$\phi_m$ (eV)	Formula	$T_m$ (K)	$\phi_m$ (eV)
Ba <sub>2</sub> Ge	1431	2.75	Eu <sub>5</sub> Sb <sub>3</sub>	1791	3.24	Pr <sub>5</sub> Sb <sub>3</sub>	1999	3.11
Ba <sub>2</sub> Si	1409	3.02	EuO	2246	3.03	Pr <sub>5</sub> Sn <sub>3</sub>	1772	3.21
Ba <sub>2</sub> Sn	1457	2.88	EuS	2534	2.85	PrAl	1714	3.17
Ba <sub>5</sub> Sb <sub>3</sub>	1405	2.90	Gd <sub>2</sub> C	2451	3.20	PrS	2478	2.60
BaGa <sub>2</sub>	1290	3.08	GdN	2994	3.23	PrSb	2384	3.30
BaSn	1416	3.29	LaS	2429	2.47	Sm	1352	2.91

CaSn	1374	3.25	LaSb	2051	3.29	Sm <sub>2</sub> C	1708	3.16
Ce <sub>2</sub> C <sub>3</sub>	2547	3.29	LaSn <sub>3</sub>	1433	3.27	Sm <sub>5</sub> Ge <sub>3</sub>	1886	3.17
CeN	3025	2.97	Nd <sub>3</sub> Ga <sub>2</sub>	1523	3.28	Sm <sub>5</sub> Sb <sub>3</sub>	1997	3.31
CeO	2365	2.90	Nd <sub>5</sub> Ge <sub>3</sub>	1911	3.27	Sm <sub>5</sub> Si <sub>3</sub>	1892	3.32
CeP	2986	3.31	Nd <sub>5</sub> Si <sub>4</sub>	1935	3.18	Sm <sub>5</sub> Sn <sub>3</sub>	1774	3.27
Eu <sub>2</sub> Ge	1521	3.27	Nd <sub>5</sub> Sn <sub>3</sub>	1816	3.22	Sr <sub>5</sub> Sb <sub>3</sub>	1309	3.27
Eu <sub>2</sub> Si	1513	3.17	NdAl	1633	3.24	SrGa <sub>2</sub>	1283	3.27
Eu <sub>2</sub> Sn	1623	3.13	NdSb	2384	3.29			

Table 4.: List of candidate metallic materials for model (C): Sm<sub>2</sub>O<sub>3</sub> contacting layer. The estimated  $T_m$  and  $\phi_m$  are also summarized.

Formula	$T_m$ (K)	$\phi_m$ (eV)	Formula	$T_m$ (K)	$\phi_m$ (eV)	Formula	$T_m$ (K)	$\phi_m$ (eV)
Al <sub>13</sub> Fe <sub>4</sub>	1434	4.28	GaNi <sub>3</sub>	1658	4.63	NiSb	1437	4.36
Al <sub>3</sub> Cr	1762	4.32	GdB <sub>4</sub>	2836	4.41	P <sub>2</sub> W	1965	4.76
Al <sub>3</sub> Ni <sub>2</sub>	1885	4.32	GdH <sub>2</sub>	1284	4.59	PW	2702	4.70
Al <sub>3</sub> Ni <sub>5</sub>	1840	4.44	Ge <sub>2</sub> Mo	1815	4.51	PrB <sub>4</sub>	2842	4.34
Al <sub>4</sub> Cu <sub>9</sub>	1327	4.26	GeMo <sub>3</sub>	2453	4.43	PrH <sub>2</sub>	1339	4.50
Al <sub>4</sub> Ni <sub>3</sub>	1899	4.40	Hf <sub>3</sub> N <sub>2</sub>	3447	4.51	RbC <sub>8</sub>	2915	5.04
Al <sub>5</sub> Co <sub>2</sub>	1493	4.26	HfB <sub>2</sub>	3489	4.43	Sc <sub>39</sub> N <sub>34</sub>	2770	4.72
Al <sub>5</sub> W	1983	4.24	HfH <sub>2</sub>	2487	4.41	Si <sub>2</sub> Mo	2263	4.44
AlCo	1899	4.36	HfP	2893	4.41	Si <sub>2</sub> Ni	1600	4.74
AlFe <sub>3</sub>	1749	4.48	HfP <sub>2</sub>	1935	4.61	Si <sub>2</sub> W	2435	4.55
AlMo <sub>3</sub>	2077	4.25	HfS	2660	4.68	Si <sub>3</sub> Mo <sub>5</sub>	2437	4.27
AlNi	1900	4.48	HoB <sub>4</sub>	2737	4.45	SiMo <sub>3</sub>	2464	4.52
AlNi <sub>3</sub>	1627	4.58	HoH <sub>2</sub>	1354	4.60	SiNi	1390	4.69
B <sub>13</sub> C <sub>2</sub>	2683	5.33	KC <sub>8</sub>	3028	5.03	SiNi <sub>2</sub>	1617	4.53
B <sub>2</sub> Mo	2707	4.65	LaB <sub>4</sub>	2349	4.28	SiNi <sub>3</sub>	1677	4.71
B <sub>2</sub> W	2738	5.06	LaH <sub>2</sub>	1332	4.48	SmB <sub>4</sub>	2800	4.39
BMo	2843	4.56	LuB <sub>4</sub>	2694	4.52	SmH <sub>2</sub>	1344	4.53
BW	3023	4.43	Mn	1537	4.29	SmN	2817	4.30
BW <sub>2</sub>	3011	4.54	Mn <sub>23</sub> C <sub>6</sub>	1841	4.32	SmP	2431	4.27
BaC <sub>6</sub>	2696	4.91	Mn <sub>29</sub> H <sub>2</sub>	1351	4.36	Ta <sub>2</sub> C	3577	4.82
Ce <sub>2</sub> O <sub>3</sub>	2484	5.48	Mn <sub>2</sub> N	1703	4.50	Ta <sub>2</sub> N	3291	4.48
CeB <sub>4</sub>	2368	4.43	Mn <sub>2</sub> P	1553	4.42	Ta <sub>3</sub> B <sub>2</sub>	2899	4.25
CeB <sub>6</sub>	2541	4.82	Mn <sub>2</sub> P	1553	4.39	Ta <sub>3</sub> B <sub>4</sub>	3315	4.45
Co	1767	4.86	Mn <sub>3</sub> Co	1364	4.33	Ta <sub>3</sub> S <sub>2</sub>	2491	4.26
Co <sub>2</sub> P	1654	4.57	Mn <sub>3</sub> Co	1364	4.38	Ta <sub>5</sub> S <sub>8</sub>	2198	4.57

Co <sub>2</sub> Si	1648	4.50	Mn <sub>4</sub> N	1653	4.58	Ta <sub>5</sub> S <sub>8</sub>	2198	4.61
Co <sub>3</sub> Ni	1467	4.53	MnAl	1474	4.35	Ta <sub>7</sub> S <sub>12</sub>	2182	4.37
Co <sub>3</sub> S <sub>4</sub>	1561	5.02	MnAl <sub>12</sub>	1354	4.25	TaB	3055	4.40
Co <sub>9</sub> S <sub>8</sub>	1455	4.84	MnAl <sub>6</sub>	1401	4.26	TaB <sub>2</sub>	3360	4.61
CoB	1735	4.91	MnB	2157	4.62	TaCo <sub>3</sub>	1837	4.45
CoGe	1490	4.48	MnB <sub>4</sub>	2401	5.04	TaH <sub>2</sub>	2125	5.08
CoH	1288	4.70	MnCo	1618	4.34	TaN	3282	4.62
CoP	1456	4.96	MnGa	1361	4.46	TaNi <sub>3</sub>	1764	4.40
CoSi	1733	4.60	MnNi <sub>3</sub>	1533	4.63	TaP	2282	4.25
CoSi <sub>2</sub>	1661	4.74	MnP	1440	4.65	TaSi <sub>2</sub>	2264	4.26
CoSn	1498	4.43	MnS <sub>2</sub>	1441	5.05	TbB <sub>4</sub>	2759	4.43
Cr <sub>2</sub> O <sub>3</sub>	2521	5.05	MnV	1677	4.25	TbH <sub>2</sub>	1427	4.58
Cr <sub>3</sub> C <sub>2</sub>	2130	4.42	Mo <sub>15</sub> N <sub>16</sub>	2333	4.85	TbH <sub>3</sub>	1286	5.22
Cr <sub>3</sub> Si	2030	4.47	Mo <sub>15</sub> N <sub>16</sub>	2333	4.75	TbP	2705	4.34
Cr <sub>7</sub> C <sub>3</sub>	2065	4.35	Mo <sub>2</sub> C	2785	4.32	Ti <sub>2</sub> C	2514	4.26
CrB <sub>4</sub>	2434	4.82	MoN	2329	4.99	Ti <sub>2</sub> O	2203	4.53
CrP	1882	4.48	MoP	2139	4.64	Ti <sub>8</sub> C <sub>5</sub>	2974	4.39
CrSi <sub>2</sub>	1756	4.42	MoP <sub>2</sub>	1600	4.56	TiB	2598	4.33
CsC <sub>8</sub>	2774	5.46	MoW	2880	4.40	TiB <sub>2</sub>	3301	4.31
Cu	1340	4.52	Nb <sub>2</sub> B <sub>3</sub>	3273	4.56	TiO	2136	4.50
DyB <sub>4</sub>	2752	4.42	Nb <sub>2</sub> N	2307	4.51	TiP	2382	4.32
DyH <sub>2</sub>	1376	4.62	Nb <sub>3</sub> B <sub>4</sub>	3183	4.33	TiS	2282	4.37
ErB <sub>4</sub>	2679	4.43	Nb <sub>3</sub> S <sub>4</sub>	1937	4.46	TmB <sub>4</sub>	2666	4.47
ErH <sub>2</sub>	1313	4.59	Nb <sub>3</sub> S <sub>5</sub>	1949	4.39	TmH <sub>2</sub>	1352	4.60
EuH <sub>2</sub>	1292	4.32	Nb <sub>5</sub> N <sub>6</sub>	2440	4.30	V <sub>2</sub> B <sub>3</sub>	2767	4.57
Fe	1784	4.55	NbB <sub>2</sub>	3293	4.49	V <sub>2</sub> N	2264	4.68
Fe <sub>2</sub> B	1576	4.77	NbCo <sub>3</sub>	1726	4.25	V <sub>2</sub> O <sub>3</sub>	2118	6.07
Fe <sub>2</sub> P	1642	4.54	NbH <sub>2</sub>	1867	5.12	V <sub>3</sub> B <sub>4</sub>	2718	4.38
Fe <sub>2</sub> W	1954	4.39	NbN	2439	5.62	V <sub>3</sub> S <sub>4</sub>	2027	4.40
Fe <sub>3</sub> Co	1449	4.64	NbP <sub>2</sub>	1839	4.41	V <sub>3</sub> Si	2198	4.31
Fe <sub>3</sub> Ge	1470	4.62	NdB <sub>4</sub>	2850	4.37	V <sub>5</sub> B <sub>6</sub>	2641	4.40
Fe <sub>3</sub> N	1861	4.92	NdH <sub>2</sub>	1337	4.52	VB	2522	4.41
Fe <sub>3</sub> P	1646	4.51	NdH <sub>3</sub>	1322	4.67	VB <sub>2</sub>	2830	4.59
Fe <sub>3</sub> Si	1643	4.67	Ni	1752	4.79	VFe <sub>3</sub>	1723	4.36
Fe <sub>3</sub> Sn <sub>2</sub>	1489	4.41	Ni <sub>12</sub> P <sub>5</sub>	1466	4.62	VN	2481	4.79
Fe <sub>9</sub> Co <sub>7</sub>	1699	4.47	Ni <sub>19</sub> Ge <sub>12</sub>	1449	4.47	VNi <sub>3</sub>	1643	4.36
FeB	1897	4.92	Ni <sub>2</sub> B	1678	4.81	VSi <sub>2</sub>	1924	4.26
FeCo	1700	4.51	Ni <sub>3</sub> B	1471	4.50	VW	2931	4.28
FeGe	1385	4.56	Ni <sub>3</sub> Ge	1723	4.63	W	3526	4.48

FeH	1481	4.67	Ni <sub>3</sub> Mo	1684	4.39	W <sub>2</sub> N <sub>3</sub>	2902	4.99
FeN	1848	5.80	Ni <sub>3</sub> P	1506	4.58	WC	2964	4.94
FeNi	1553	4.72	Ni <sub>3</sub> S <sub>2</sub>	1359	4.95	YB <sub>4</sub>	2951	4.45
FeNi <sub>3</sub>	1498	4.83	Ni <sub>3</sub> Sn	1434	4.61	Zn <sub>3</sub> N <sub>2</sub>	1579	4.41
FeP	1430	4.97	Ni <sub>3</sub> Sn <sub>2</sub>	1500	4.39	ZnNi	1346	4.48
FeS	1452	4.77	Ni <sub>3</sub> Sn <sub>4</sub>	1285	4.36	ZrB <sub>2</sub>	3325	4.24
FeSn	1388	4.42	Ni <sub>4</sub> B <sub>3</sub>	1499	4.82	ZrH <sub>2</sub>	1910	4.28
Ga <sub>31</sub> Mo <sub>6</sub>	1355	4.26	Ni <sub>4</sub> Sn <sub>3</sub>	1501	4.41	ZrN	3252	4.44
Ga <sub>3</sub> Ni <sub>2</sub>	1509	4.36	Ni <sub>4</sub> W	1766	4.31	ZrP	2537	4.30
Ga <sub>3</sub> Ni <sub>5</sub>	1504	4.44	Ni <sub>5</sub> Ge <sub>3</sub>	1450	4.48	ZrP <sub>2</sub>	1764	4.51
Ga <sub>9</sub> Ni <sub>13</sub>	1505	4.35	Ni <sub>5</sub> P <sub>4</sub>	1361	4.68	ZrS	2436	4.62
GaCo	1497	4.42	Ni <sub>9</sub> S <sub>8</sub>	1331	4.71	ZrSi	2507	4.24
GaFe <sub>3</sub>	1667	4.67	NiGe	1446	4.54	ZrSi <sub>2</sub>	2200	4.33
GaMo <sub>3</sub>	2461	4.30	NiH	1276	4.64			

Table 5.: List of candidate metallic materials for model (D): BaS contacting layer. The estimated  $T_m$  and  $\phi_m$  are also summarized.

SUPPLEMENTAL MATERIAL

## Computational material screening for electrode materials of BaSi<sub>2</sub> solar cells

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### 1. Data list of work functions

Table S1 lists the work functions of elemental metals estimated by the density functional theory (DFT) calculations and the machine learning model [S1] together with reference values [S2].

Table S1 Work functions of elemental metals estimated by DFT calculations and the machine learning model [S1] together with reference values [S2]. Estimations are for (100) orientations. Reference values are for (100) if available; otherwise, for polycrystalline samples.

Formula	Work function (DFT) [eV]	Work function (machine learning) [eV]	Work function (reference [S2]) [eV]
Ag	4.39	4.22	4.64
Al	4.38	4.25	4.2
Au	5.23	4.90	5.47
Ba	2.40	2.33	2.52
Be	3.93	3.86	4.98
Ca	2.76	2.79	2.87
Cs	1.99	2.01	1.95
Cu	4.65	4.61	5.1
Ga	4.37	4.33	4.32
Hf	3.69	3.57	3.9

In	3.95	4.01	4.09
K	2.22	2.38	2.29
Li	3.06	3.01	2.93
Mg	3.69	3.51	3.66
Mo	3.98	4.00	4.53
Na	2.66	2.83	2.36
Nb	3.67	3.75	4.02
Os	4.89	4.81	5.93
Pb	3.85	3.94	4.25
Pd	5.23	5.03	5.22
Pt	5.81	5.59	5.64
Rb	2.17	2.21	2.261
Re	4.52	4.42	4.72
Rh	5.23	4.96	4.98
Ru	4.60	4.44	4.71
Sc	3.32	3.23	3.5
Sn	4.27	4.29	4.42
Ta	3.90	4.22	4.15
Ti	3.70	3.49	4.33
V	3.84	4.00	4.3
W	4.21	4.36	4.63
Zn	4.60	4.07	3.63
Zr	3.68	3.41	4.05

## 2. Validation of the screening workflow on pn-junction Si solar cells

To validate our screening workflow, we searched for electrode materials for pn-junction crystalline Si solar cells. The device model for simulations consisted of an n-type Si layer (100 nm) on the top side and a p-type Si layer (200  $\mu\text{m}$ ) on the bottom side. The electron and hole concentrations in the n- and p-type layers were  $1 \times 10^{19} \text{ cm}^{-3}$  and  $1 \times 10^{16} \text{ cm}^{-3}$ , respectively. The permittivity, bandgap, electron affinity, effective density of states of the conduction band, effective density of states of the valence band, electron mobility, and hole mobility were 11.9, 1.12 eV, 4.05 eV,  $2.86 \times 10^{19} \text{ cm}^{-3}$ ,  $2.66 \times 10^{19} \text{ cm}^{-3}$ ,  $1450 \text{ cm}^2/\text{V}\cdot\text{s}$ , and  $505 \text{ cm}^2/\text{V}\cdot\text{s}$ , respectively, according to ref. [S3]. The optical absorption coefficients were taken from ref. [S4]. Because wxAMPS does not accept Auger recombination coefficients, acceptor-type midgap defects

were assumed to simulate realistic Si materials. We assumed the density, energy level, and capture cross section to be  $1 \times 10^{12} \text{ cm}^{-3}$ , 0.56 eV, and  $1 \times 10^{-16} \text{ cm}^2$ , respectively. This led to a carrier lifetime of approximately 1 ms. The simulation temperature was 300 K, and the effective surface recombination speed was  $1 \times 10^7 \text{ cm/s}$ . The top and bottom reflectances were 0 and 1, respectively.

Figure S1 shows the power conversion efficiency of the pn-junction Si solar cells as functions of the work functions of the bottom and top electrodes. These results indicate the range of work functions that yield high power conversion efficiency: Specifically,  $\geq 5.45 \text{ eV}$  for the bottom electrode and  $\leq 3.65 \text{ eV}$  for the top electrode.

Then, computational material screening was performed. For the validation, the search space was confined to elements excluding noble gases, radioactive elements, and actinoids. The melting point threshold was set to 300 K. Table S2 summarizes the candidate materials in descending order of electrical conductivity (accurately, electrical conductivity divided by the relaxation time. Please see the main text for details). Work function criteria were not considered to prepare this table. If we apply the work function criteria, only Na remains as a candidate. However, Na is highly reactive with air and is therefore not used in practical solar cells. Additionally, a common approach is to heavily dope with impurities to avoid the effect of Fermi level pinning and form ohmic contacts on Si by taking advantage of its excellent dopability. Therefore, ignoring the work function criterion aligns with the design concept of practical Si solar cells. However, if we consider other semiconductors that do not significantly suffer from Fermi level pinning, the work function criteria would be useful for effective screening. Table S2 shows that Al, In, Ag, etc. are promising candidates. This result agrees with the electrode materials (Al and Ag) used in practical Si solar cells [S5]. It is avoided probably because of its low melting point, scarcity of resources, and high cost. Thus, our screening workflow has been shown to reach practical electrode materials for crystalline Si solar cells.

Figure S1 Power conversion efficiency of pn-junction solar cells simulated by wxAMPS as functions of work function of (a) bottom and (b) top electrodes.

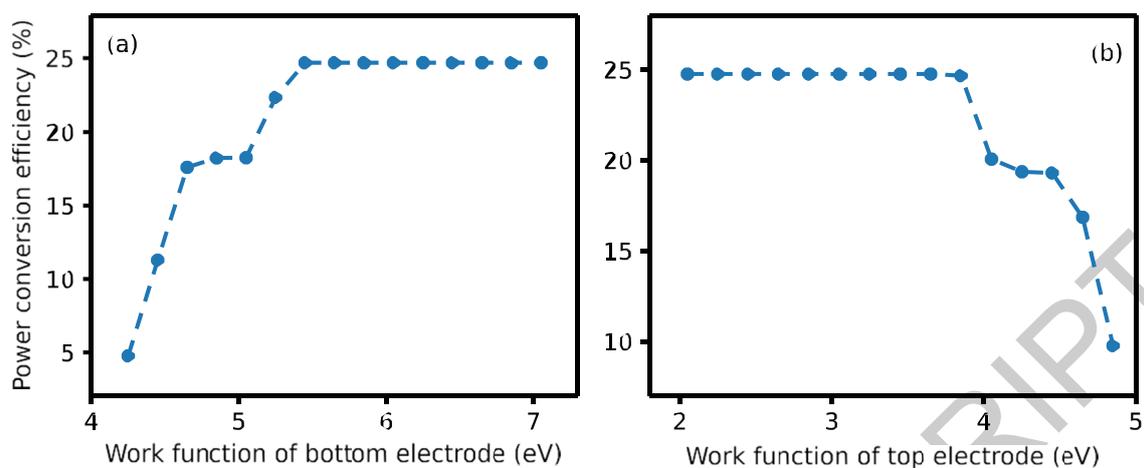


Table S2 List of elements that passed computational material screening. The considered criteria included bandgap, phase stability, interface reactivity, and melting point. The estimated work function is also listed, but was not used for screening. The elements are listed in descending order of electrical conductivity divided by the relaxation time.

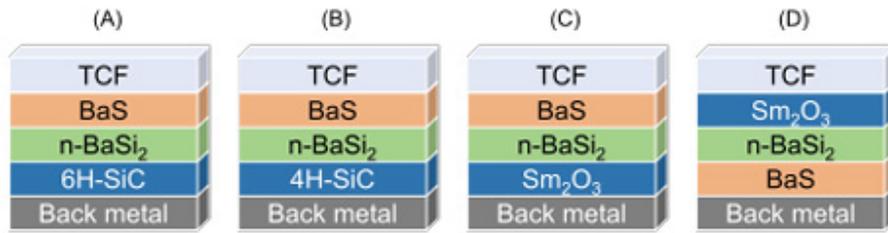
Formula	mp-ID	Melting point (K)	Work function (eV)	Electrical conductivity (S/cm·s)
Al	mp-134	991	4.19	$3.13 \times 10^6$
In	mp-85	404	4.05	$1.99 \times 10^6$
Ag	mp-8566	1208	4.19	$1.66 \times 10^6$
Zn	mp-79	647	4.03	$1.65 \times 10^6$
Pb	mp-20483	566	3.96	$1.64 \times 10^6$
Au	mp-81	1277	4.87	$1.56 \times 10^6$
Cd	mp-94	617	3.93	$1.23 \times 10^6$
Tl	mp-82	562	3.81	$1.04 \times 10^6$
Na	mp-10172	350	2.80	$7.29 \times 10^5$
Be	mp-87	1542	4.46	$7.22 \times 10^5$
Ga	mp-142	314	4.29	$5.40 \times 10^5$
Sb	mp-104	853	4.70	$2.82 \times 10^4$
Sn	mp-117	503	4.29	$2.71 \times 10^4$
Ge	mp-32	1176	4.74	$1.76 \times 10^3$

## References

[S1] Schindler P, Antoniuk ER, Cheon G, et al. Discovery of stable surfaces with extreme work functions by high-throughput density functional theory and machine learning. *Adv Funct Mater.* 2024;34(19): 2401764.

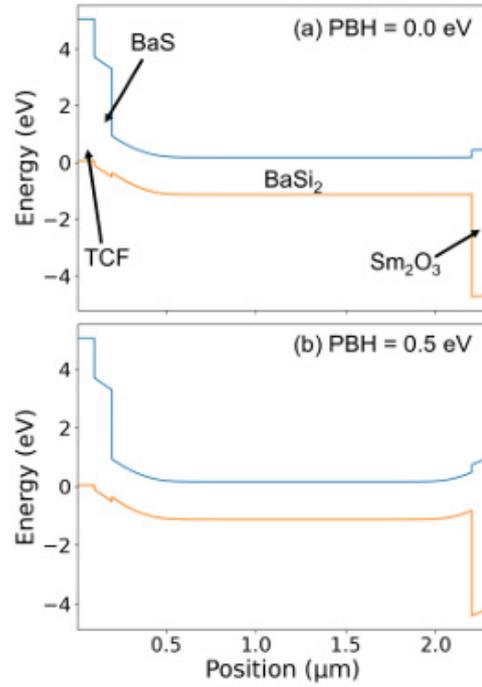
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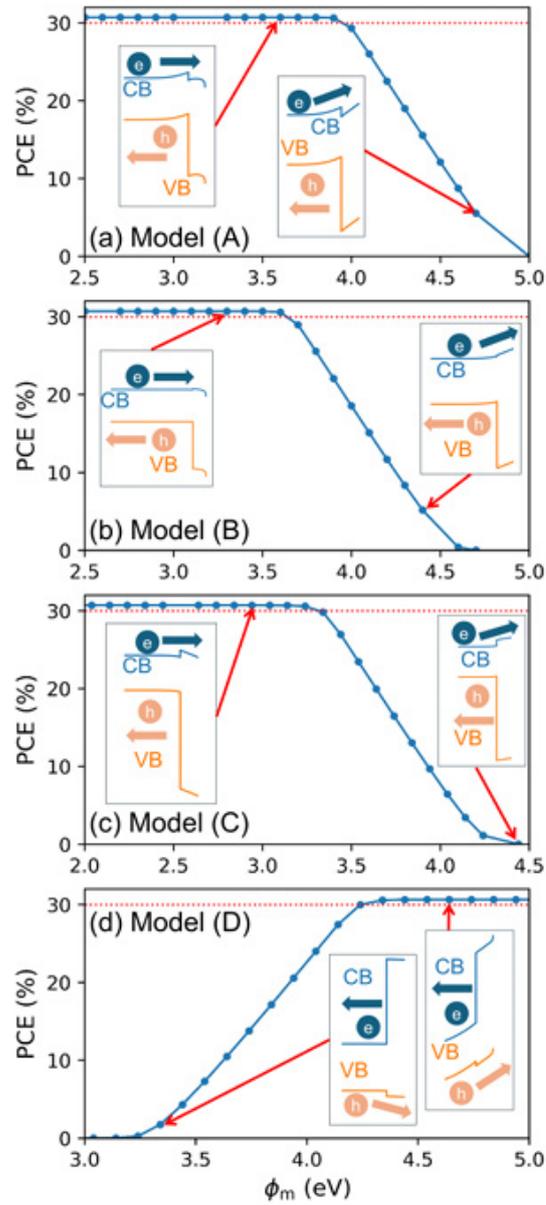
**Figure 1.** Device models used for simulations.

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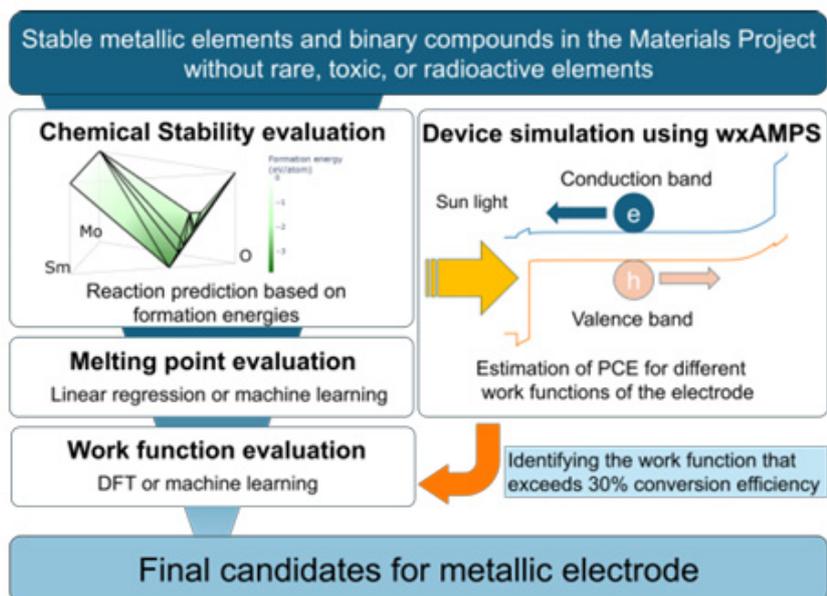


**Figure 2.** The calculated band alignments of the model (C) in Fig. 1 with PBH = (a) 0.0 and (b) 0.5 eV under dark conditions. Upper blue line denotes the conduction band minimum while the lower orange line denotes the valence band maximum.

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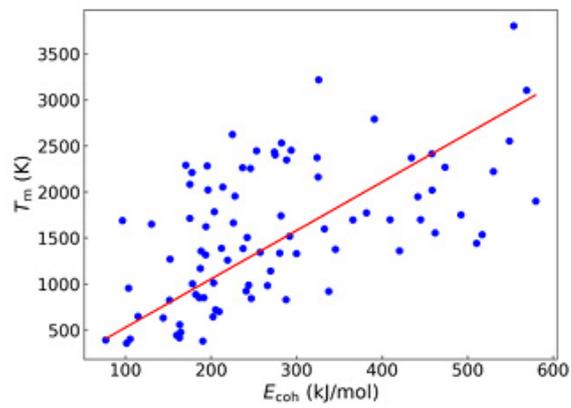


**Figure 3.** (a)–(d) Simulated PCE of solar cells as functions of the  $\phi_m$  of metallic electrodes in models (A)–(D), where the electrodes are in contact with 6H-SiC, 4H-SiC,  $\text{Sm}_2\text{O}_3$ , and BaS, respectively. The red dashed line indicates a PCE of 30%. The insets show the band alignments near the back electrode for specific work functions. CB and VB denote the conduction and valence bands, respectively.



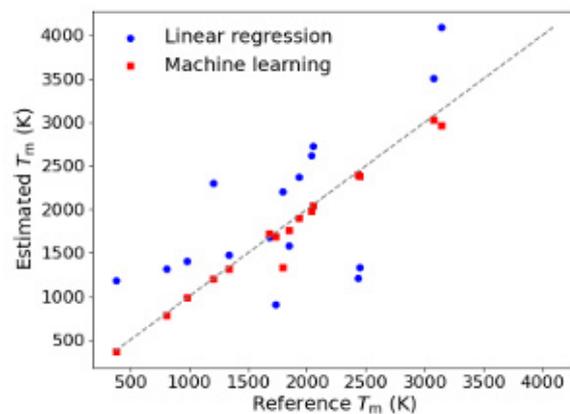
**Figure 4.** Workflow of computational material screening for metallic electrodes of solar cells proposed in this study.

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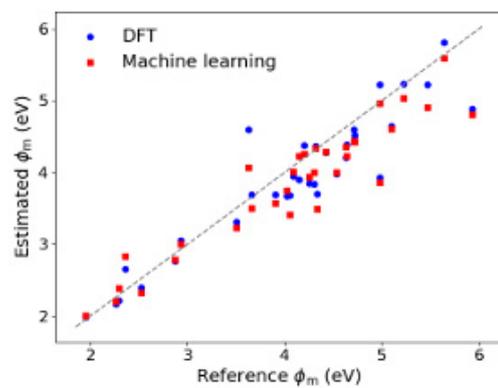
**Figure 5.**  $T_m$  plotted against  $E_{\text{coh}}$  of randomly selected binary metallic compounds, along with the regression line.

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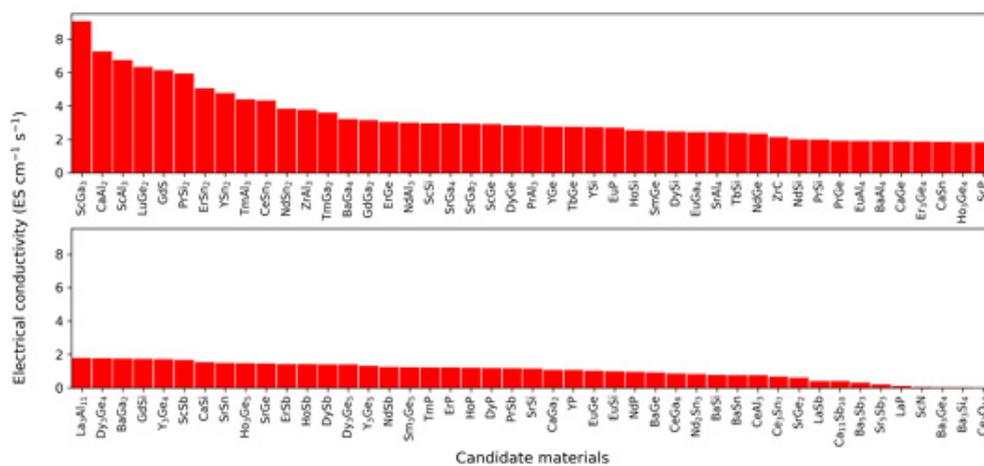
**Figure 6.** Comparison of the  $T_m$  of binary metallic compounds estimated by the linear regression (circles) and the machine learning model [33] (squares) with the reference values.

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**Figure 7.** Comparison of the  $\phi_m$  of elemental metals estimated by DFT and the machine learning model [39]. The surface orientation selected was (100) for all data.

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**Figure 8.** Electrical conductivity of the candidate materials for model (A). The electrical conductivity divided by the relaxation time is shown.

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